



High Performance Thin-Film Coatings: Ensuring Nanoscale Manufacturing Integrity

30th November 2010
Institute of Physics, London, UK

CEMMNT (The Centre of Excellence in Metrology for Micro and Nano Technologies) and the NanoKTN are set to co-host a brand new and exclusive event on 30th November 2010 focusing on the current challenges and opportunities for the development of new processes, materials and measurement technologies in the thin-films and coatings industry.

The increasingly aggressive demands of important manufacturing sectors have fuelled the emergence of new functional coatings, wear protection, enhancing the service life of tooling or protection from thermal and atmospheric influences, these important new materials need to perform consistently at thicknesses down to the submicron range, and require specialised processing regimes with the reliability and robustness necessary to confidently control performance characteristics and minimise defects at the molecular and atomic scale.

The development of thin film systems is invariably associated with a range of materials and processing challenges... To address these significant challenges, two of the UK's foremost nanotechnology organisations, CEMMNT and the NanoKTN, have organised an event that brings together leading speakers from industry and academia to present the latest thinking on the following thin-film coating themes:

- High integrity structural coatings
- High performance electronic films
- Functional patterned surfaces

In addition to excellent networking opportunities, this unique event includes an exhibition with manufacturers of processing and measurement and characterisation equipment available to discuss your current and future requirements,

Speakers & Topics Include:

- *Welcome & Introduction, Dr Martin Kemp (NanoKTN) & Paul Newbatt (CEMMNT)*
- *Production of Nanoparticle Coatings for High Performance Structural Applications, Alistair Kean (Mantis Deposition Ltd)*
- *The Structure, Integrity & Adhesion of Ceramic Coatings using X-Ray Tomography and Mechanical Testing, Ian Shapiro (School of Materials, University of Manchester)*
- *Recent Advances in Metrology for Mechanical Testing of Thin Films, Mark Gee (NPL)*
- *Ensuring Good Conformity for Thin-Film Photovoltaics, Mike Walls (Loughborough University)*
- *Optimising Lifetime Performance of Thin Films for the Plastic Electronic Industry, Robert Gunn (Oxford Instruments)*
- *Investigating the Conformity & Structure of Industrial Thin Films by EM and Surface Analysis Techniques, Alison Crossley (Bebroke Nano)*
- *ANSIN: How to Leverage from a World Leader, Robert Bowman (Centre for Nanostructured Media, Queen's University, Belfast)*
- *Digital Holographic Microscopy for Real Time 3D Surface Analysis, David Morgan (Windsor Scientific)*
- *Public Funding Calls & Grant Schemes, Christian Inglis (Technology Strategy Board)*

Registration

To register for this event please contact Natasha Taylor at Natasha.taylor@nanoktn.com. The cost to register for the event is just £145 +VAT. Please note, a discounted rate of £95 +VAT will be charged to members of the NanoKTN and supporting organisations.

Exhibition

There is also an opportunity for companies to exhibit at the event. The cost to exhibit is £250 +VAT and includes: 1 delegate pass, space for 2 banner stands, table for literature and/or product demonstration, A4 delegate pack insert, and company logo & 50-word profile on event website. To book your place to exhibit please contact Natasha Taylor at Natasha.taylor@nanoktn.com

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